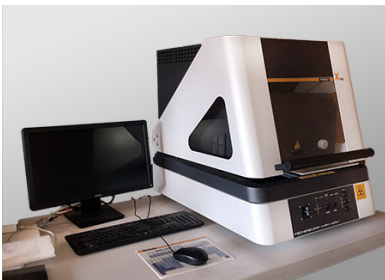


Instant Analysis



Fischerscope XDAL

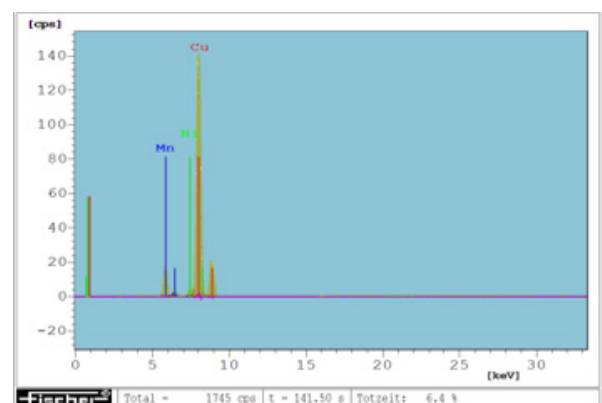
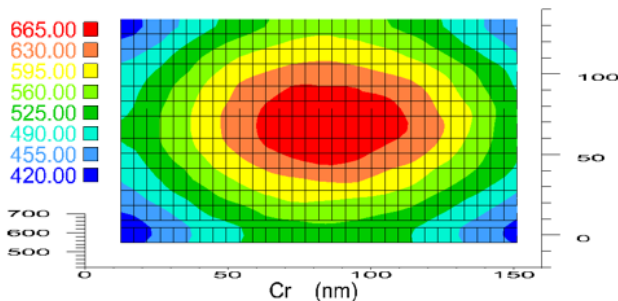
The Fischerscope XDAL is an x-ray fluorescence (XRF) measurement tool for industrial applications. XRF works by exciting the sample material and detecting the characteristic x-ray emission coming from the sample. The collected data can be used to calculate the material composition or the thickness of a multilayer thin film layer stack of a sample. A motorized XYZ unit allows measurement of profiles or x-y film thickness mappings.

Technical Data

Detector Lower Limit	P, Atomic Number 15
Limitations Material Analysis Measurement	± 50 ppm
Film Thickness	0,05 - 5000 µm (depends on Element)
Limitations Film Thickness Measurement	No repeated elements in the layer stack
Sample Size	Flat: 600 x 600 x 8 mm 3D: 250 x 250 x 200 mm
X-Y Positioning Automatic Measurement Size	150 x 250 mm

Artikel Nr. 5 Cr/Glas

Block Nr. 40: Erika (static) Cr - Glass 120 mm Test - 2



■ Bezug: Messspektrum
 ■ Streuspektrum
 ■ Summenspektrum
 ■ Residuum
 Messparameter Bezugsspektrum:
 Hochspannung = 50 kV (075) Prim. Filter = Al1000
 Kollimator 3 = 0.60 Dm. Anodenstrom 324 uA
 Messdistanz = 0.11 mm
 Analysergebnisse: (%)
 ■ 29 Cu = 83.08
 ■ 25 Mn = 13.85
 ■ 28 Ni = 3.07